WHAT IS CLAIMED IS:

[Claim 1] An inspection apparatus for electronic component processing equipment, the inspection apparatus comprising:

a laser radiator provided to radiate laser;

a reflector configured to reflect the laser, radiated by the laser radiator, to top surfaces of electronic components loaded onto a loading element to make long linear laser radiated in one direction onto the top surfaces of the electronic components;

a checking camera configured to photograph the laser reflected to the top surfaces of the electronic components by the reflector;

a mounting bracket provided to mount the reflector; and

a controller configured to analyze seating states of the electronic components by analyzing an image taken by the checking camera;

wherein the mounting bracket comprises:

a close contact portion configured to bring the reflector into close contact with a flat close contact surface of the mounting bracket by pressing the reflector toward the flat close contact surface; and

an alignment portion configured to align the reflector by bringing the reflector into close contact with an alignment surface of the mounting bracket.

[Claim 2] The inspection apparatus of claim 1, wherein the close contact portion has an elastic member configured to enable elastic compression and restoration to press the reflector toward the close contact surface.

[Claim 3] The inspection apparatus of claim 1, wherein the close contact portion is configured such that a first opposing surface thereof facing the close contact surface is provided as an elastically deformable surface configured to enable elastic deformation and restoration to press the reflector toward the close contact surface.

[Claim 4] The inspection apparatus of claim 3, wherein:

the mounting bracket has an insertion groove configured such that a part of the reflector can be inserted thereinto;

wall surfaces defining the insertion groove include:

the close contact surface configured such that the reflector pressed by the close contact portion comes into close contact therewith;

the first opposing surface configured to face the close contact surface;

an alignment surface configured such that one side of the reflector comes into close contact therewith;

a second opposing surface configured to face the alignment surface; and

a support surface configured to support a bottom end of the reflector; and

the close contact portion includes the first opposing surface.

[Claim 5] The inspection apparatus of claim 4, wherein:

the first opposing surface is rotatably provided such that when the first opposing surface is rotated to face the close contact surface, the close contact portion is in a state of pressing the reflector; and

the inspection apparatus further comprises a fixer configured to fix the first opposing surface so that the close contact portion maintains the state of pressing the reflector.

[Claim 6] The inspection apparatus of claim 1, wherein the alignment portion has an elastic member configured to enable elastic compression and restoration to press the reflector toward the alignment surface.

[Claim 7] The inspection apparatus of claim 1, wherein the alignment portion is configured such that a second opposing surface thereof facing the alignment surface is provided as an elastically deformable surface configured to enable elastic deformation and restoration to press the reflector toward the alignment surface.

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[Claim 8] The inspection apparatus of claim 7, wherein:

the mounting bracket has an insertion groove configured such that a part of the reflector can be inserted thereinto;

wall surfaces defining the insertion groove include:

a close contact surface configured such that the reflector comes into close contact therewith;

a first opposing surface configured to face the close contact surface;

the alignment surface configured such that one side of the reflector pressed by the alignment portion comes into close contact therewith;

the second opposing surface configured to face the alignment surface; and

a support surface configured to support a bottom end of the reflector; and

the alignment portion includes the second opposing surface.

[Claim 9] The inspection apparatus of claim 8, wherein:

the second opposing surface is provided to selectively move forward and backward toward and away from the alignment surface so that when the second opposing surface moves forward toward the alignment surface, the alignment portion is in a state of pressing the reflector; and

the inspection apparatus further comprises a fixer configured to fix the second opposing surface so that the alignment portion maintains the state of pressing the reflector.

[Claim 10] An inspection apparatus for electronic component processing equipment, the inspection apparatus comprising:

a laser radiator provided to radiate laser;

a reflector configured to reflect the laser, radiated by the laser radiator, to top surfaces of electronic components loaded onto a loading element to make long linear laser radiated in one direction onto the top surfaces of the

electronic components;

a checking camera configured to photograph the laser reflected to the top surfaces of the electronic components by the reflector;

a mounting bracket provided to mount the reflector; and

a controller configured to analyze seating states of the electronic components by analyzing an image taken by the checking camera;

wherein the mounting bracket has a close contact portion configured to bring the reflector into close contact with a flat close contact surface of the mounting bracket by pressing the reflector toward the flat close contact surface,

wherein the close contact portion is configured such that a first opposing surface thereof facing the close contact surface is provided as an elastically deformable surface configured to enable elastic deformation and restoration to press the reflector toward the close contact surface,

wherein:

the mounting bracket has an insertion groove configured such that a part of the reflector can be inserted thereinto;

wall surfaces defining the insertion groove include:

the close contact surface configured such that the reflector pressed by the close contact portion comes into close contact therewith;

the first opposing surface configured to face the close contact surface;

an alignment surface configured such that one side of the reflector comes into close contact therewith;

a second opposing surface configured to face the alignment surface; and

a support surface configured to support a bottom end of the reflector; and

the close contact portion includes the first opposing surface,

wherein:

the first opposing surface is rotatably provided such that when the first opposing surface is rotated to face the close contact surface, the close contact portion is in a state of

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pressing the reflector; and

the inspection apparatus further comprises a fixer configured to fix the first opposing surface so that the close contact portion maintains the state of pressing the reflector.

[Claim 11] An inspection apparatus for electronic component processing equipment, the inspection apparatus comprising:

a laser radiator provided to radiate laser;

a reflector configured to reflect the laser, radiated by the laser radiator, to top surfaces of electronic components loaded onto a loading element to make long linear laser radiated in one direction onto the top surfaces of the electronic components;

a checking camera configured to photograph the laser reflected to the top surfaces of the electronic components by the reflector;

a mounting bracket provided to mount the reflector; and

a controller configured to analyze seating states of the electronic components by analyzing an image taken by the checking camera;

wherein the mounting bracket comprises an alignment portion configured to align the reflector by bringing the reflector into close contact with an alignment surface of the mounting bracket,

wherein the alignment portion is configured such that a second opposing surface thereof facing the alignment surface is provided as an elastically deformable surface configured to enable elastic deformation and restoration to press the reflector toward the alignment surface,

wherein:

the mounting bracket has an insertion groove configured such that a part of the reflector can be inserted thereinto;

wall surfaces defining the insertion groove include:

a close contact surface configured such that the reflector comes into close contact therewith;

a first opposing surface configured to face the close contact surface;

the alignment surface configured such that one side of the reflector pressed by the alignment portion comes into close contact therewith;

the second opposing surface configured to face the alignment surface; and

a support surface configured to support a bottom end of the reflector; and

the alignment portion includes the second opposing surface,

wherein:

the second opposing surface is provided to selectively move forward and backward toward and away from the alignment surface so that when the second opposing surface moves forward toward the alignment surface, the alignment portion is in a state of pressing the reflector; and

the inspection apparatus further comprises a fixer configured to fix the second opposing surface so that the alignment portion maintains the state of pressing the reflector.

[Claim 12] The inspection apparatus of any one of claim 4, 8, 10 or 11, wherein an adhesive is used between the reflector and the close contact surface to attach the reflector to the close contact surface, at least a part of the insertion groove is provided as an accommodation space which accommodates excess adhesive moving out between the reflector and the close contact surface.

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